IAP20 RCG'STOTTVO 17 MAR 2006

	Based on Form PTO-1449 (3/90)						ATTY. DOCKET NO. 930086-20	SERVENO. 2/2/U/ TO BE ASSIGNED			
		LIST OF	REFERENCES ((Use several shee				APPLICANT Ki-Won JUN, et al.				
							FILING DATE CONCURR	GROUP 179 3			
Ī		U.S. PATENT DOCUMENTS									
	EXAMINER INITIAL	IAL DOCUMENT NUMBER DATE					NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	1	~AA	6,740,783 B1		05/25/04	Jun et al.		568	698		
Ī		ĄВ	5,254,596		10/19/93	Irick, Jr. et al.		518	728		
l		AC	4,590,176		05/20/86	Hoek et al.		502	307		
₫	M	AD	4,536,485		08/20/85	Topp-Jorgensen		502	62		
	7	AE									
	AF										
FOREIGN PATENT DOCUMENTS											
ſ			DOCUMENT NUMBER		DATE		COUNTRY	CLASS	SUBCLASS	TRANS	LATION
	, 1	7			21125/22					YES	NO
		AG	2000-0002477		01/15/00	Korea				Abst.	
	90	AH	100228748		08/11/99	Korea				Abst.	
		AJ 1020040051032		06/18/04	Korea	$\langle \ \rangle \sim 4$	/		Abst.		
ſ		AJ 57-007432 AK 59-016845 AL 59-42333		01/14/82	Japan				Abst.		
Ī				01/28/84	Japan	7//\			Abst.		
Ì				=	03/08/84	Japan	7				Х
ļ	1.	AM	61-017528		01/25/86	Japan				Abst.	
(WIN	AN 0 291 937		03/22/89	Europ	e			Abst.		
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		AO									
		AP								· 	
		AQ		70					, 		
EXAMINER DATE CONSIDERED									9/0-	7	
Ī	EXAMINER citation if not	R: Initial if r	elerence considerence and not consider	d, whether or r lered. Include o	ot citation is in con copy of this form w	oformance with MPEP 609. Draw line through / //					
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